

## Hspice HW1

(1) Compare both I-V curves and make comments on their differences.

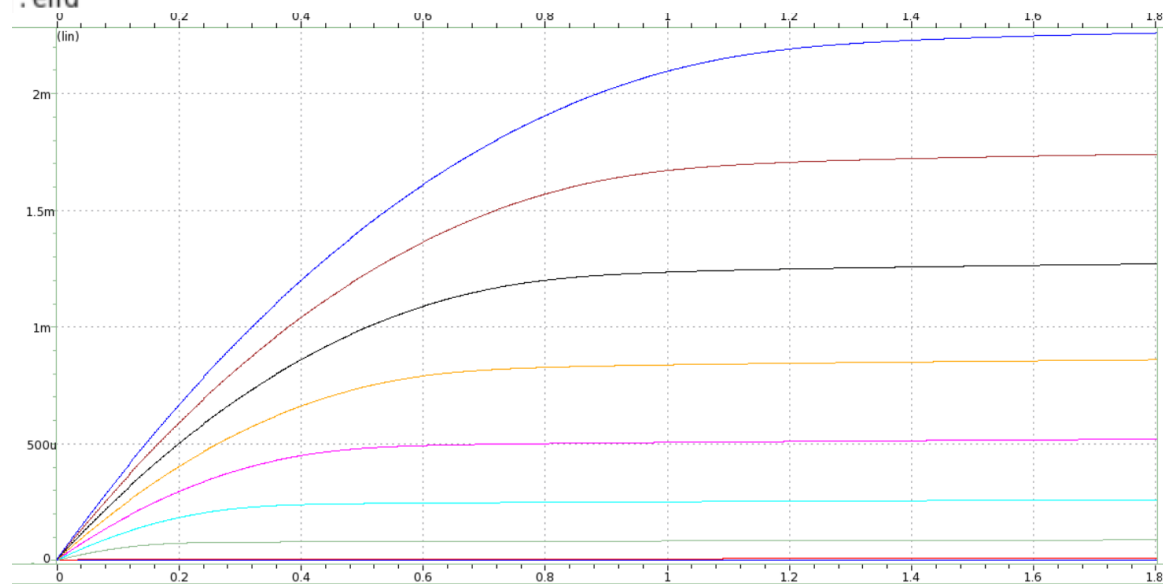
W=18um, L=1.8um

```
Hw1_1_long channel
.option post
*circuit
mm vd vg vs gnd n_18_mm l=1.8u w=18u AS="0.48u*18u" AD="0.48u*18u" PS="0.96u
+18u" PD="0.96u+18u"

*source
vdd vd 0 dd
vgg vg 0 gg
vss vs 0 0

*sim
.dc dd 0 1.8 lm sweep gg 0 1.8 0.2

.lib "/RAID2/COURSE/AICIntro/AICIntro071/U18_model/U18_Spice_model/
mm180_reg18_v124.lib" tt
.end
```



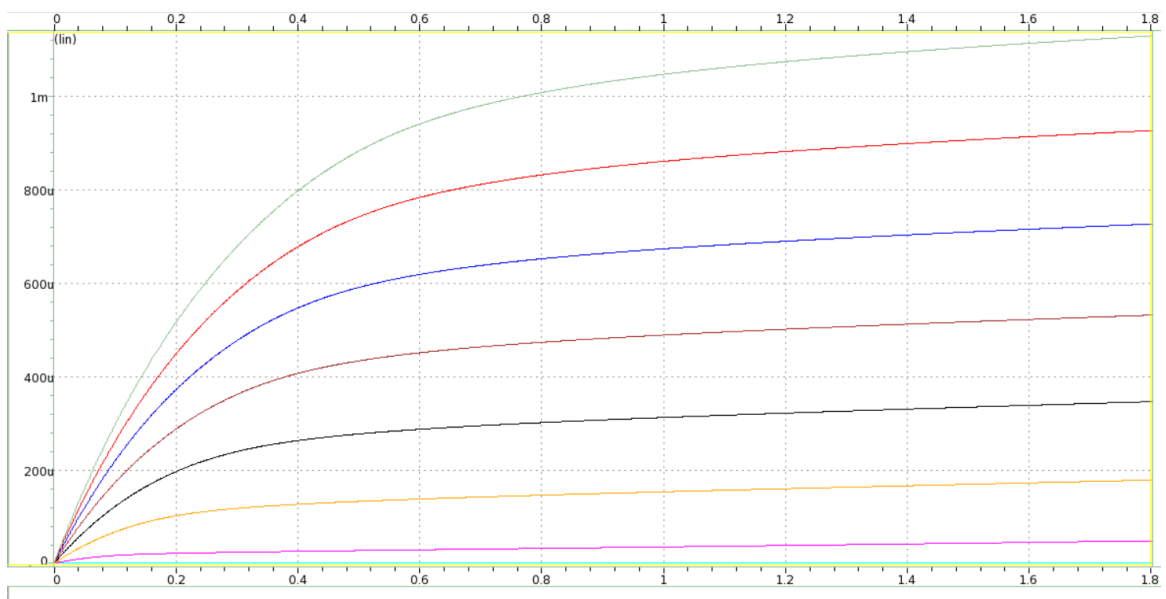
X-axis:  $V_{DS}$ , Y-axis:  $I_{ds}$ ,  $V_{GS}$  varies from 0 to 1.8V, step=0.2V

W=1.8um, L=0.18um

```
Hw1_1_short channel
.option post
*circuit
mm vd vg vs gnd n_18_mm l=0.18u w=1.8u AS="0.48u*1.8u" AD="0.48u*1.8u"
PS="0.96u+1.8u" PD="0.96u+1.8u"

*source
vdd vd 0 dd
vgg vg 0 gg
vss vs 0 0
*sim
.dc dd 0 1.8 1m sweep gg 0 1.8 0.2

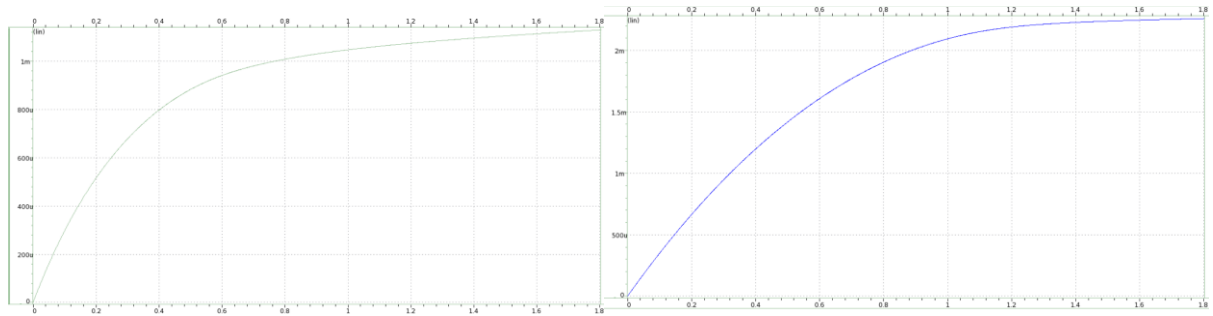
.lib "/RAID2/COURSE/AICIntro/AICIntro071/U18_model/U18_Spice_model/
mm180_reg18_v124.lib" tt
.end
```



X-axis:  $V_{DS}$ , Y-axis:  $I_{ds}$ ,  $V_{GS}$  varies from 0 to 1.8V, step=0.2V

## Lab1 summary:

We can see that  $I_D$  will increase as  $V_{DS}$  increase at first. However, When  $V_{DS} > V_{GS} - V_{Th}$ , the transistor enters the saturation region. This means that in the ideal condition  $I_D$  won't increase as  $V_{DS}$  increase. The small change of  $I_D$  after entering the saturation region is due to channel length modulation.



In the above pictures, we can see that when  $V_{GS}$  is the same, short channel's  $I_{D,sat}$  is smaller than the long channel's  $I_{D,sat}$ . Take these two pictures as example. Both pictures are when  $V_{GS} = 1.8V$ . The short channel's  $I_{D,sat}$  is about 1mA, and the long channel's  $I_{D,sat}$  is about 2mA. This is because the velocity saturation. I will clearly illustrate it in the Lab3.

**(2) Compare the simulated current and the calculated current at different conditions.**

(a)  $V_{GS}=1.8V$ ,  $V_{DS}=1.8V$ ,  $W/L=18\mu m/1.8\mu m$

$I_{D,calculated}$

$$=0.5 \cdot 314.1/10000 \cdot (3.4515 \cdot 10^{-11}) / (4.2 \cdot 10^{-9}) \cdot (18\mu/1.8\mu) \cdot (1.8 - 0.3075)^2 = 2.875\text{mA}$$

$I_{D,simulation}$

$$= 2.259\text{mA}$$

It is found that the  $I_{D,calculated}$  and  $I_{D,simulation}$  is almost the same. And a slight difference between them is because Hspice consider a lot of effect which we didn't consider in the formula  $I_D = 0.5 \mu_n C_{ox} (W/L) (V_{GS} - V_{Th})^2$ .

```
Hw1_2_VGS=1.8V VDS=1.8V W/L=18u/1.8u
.option post
*circuit
mm vd vg vs gnd n_18_mm l=1.8u w=18u AS="0.48u*18u" AD="0.48u*18u" PS="0.96u
+18u" PD="0.96u+18u"

*source
vdd vd 0 1.8
vgg vg 0 1.8
vss vs 0 0
*sim
.tran ln 10m

.lib "/RAID2/COURSE/AICIntro/AICIntro071/U18_model/U18_Spice_model/
mm180_reg18_v124.lib" tt
.end
```



(b)  $V_{GS}=0.8V$ ,  $V_{DS}=1.8V$ ,  $W/L=18\mu m/1.8\mu m$

$I_{D,calculated}=0.5 \cdot 314.1/10000 \cdot (3.4515 \cdot 10^{-11}) / (4.2 \cdot 10^{-9}) \cdot (18\mu/1.8\mu) \cdot (0.8 - 0.3075)^2 = 0.313mA$

$I_{D,simulation}=0.261.5mA$

The difference between the calculation result and the simulation result is larger than the difference in part(a). However, this difference is still acceptable. Because the  $n_{18\_mm}$  consider more than 40 parameter, and the calculated result only consider few parameter. Also, from High  $V_{GS}$  to LOW  $V_{GS}$ , The  $I_D$  will be lower. It is because  $I_{out} (I_D) = g_m \cdot V_{GS} (V_{in})$  in the small signal model.

```
Hw1_2_VGS=0.8V VDS=1.8V W/L=18u/1.8u
.option post
mml vd vg vs gnd n_18_mm l=1.8u w=18u AS="0.48u*18u" AD="0.48u*18u" PS="0.96u
+18u" PD="0.96u+18u"
*source
vd vd 0 1.8
vg vg 0 0.8
vsb vs 0 0
.tran 10n 50u
.lib "/RAID2/COURSE/AICIntro/AICIntro071/U18_model/U18_Spice_model/
mml80_reg18_v124.lib" tt
.end
```



(c)  $V_{GS}=1.8V$ ,  $V_{DS}=1.8V$ ,  $W/L=1.8\mu m/0.18\mu m$

$I_{D,calculated}$

$=V_{sat} \cdot W \cdot C_{ox} \cdot (V_{GS} - V_{TH}) = 5.2 \cdot 10^4 \cdot 1.8\mu \cdot (3.4515 \cdot 10^{-11}) / (4.2 \cdot 10^{-9}) \cdot (1.8 - 0.3075) = 1.148mA$

$I_{D,simulation}$

$=1.135mA$

Using the formula  $I_D = 0.5 \cdot \mu_n \cdot C_{ox} \cdot W/L \cdot (V_{GS} - V_{TH})^2$  may get the same result as in part a. However, it is found that there's a big gap between the  $I_{D,simulation}$  and the  $I_{D,calculation}$ . Thus, it has to change different formula for this short channel effect. The formula  $I_D = V_{sat} \cdot W \cdot C_{ox} \cdot (V_{GS} - V_{TH})$  is used. The short channel devices have to consider the velocity saturation, which will restrict our  $I_D$ .

```

Hw1_2_VGS=1.8V VDS=1.8V W/L=1.8u/0.18u
.option post
mml vd vg vs gnd n_18_mm l=0.18u w=1.8u AS="0.48u*1.8u" AD="0.48u*1.8u"
PS="0.96u+1.8u" PD="0.96u+1.8u"
*source
vd vd 0 1.8
vg vg 0 1.8
vsc vs 0 0
.tran 10n 50u
.lib "/RAID2/COURSE/AICIntro/AICIntro071/U18_model/U18_Spice_model/
mml80_reg18_v124.lib" tt
.end

```



(d) VGS=0.8V, VDS=1.8V, W/L=1.8um/0.18um

ID,calculated

$$=V_{sat} \cdot W \cdot C_{ox} \cdot (V_{GS} - V_{TH}) = 5.2 \cdot 10^4 \cdot 1.8u \cdot (3.4515 \cdot 10^{-11}) / (4.2 \cdot 10^{-9}) \cdot (0.8 - 0.3075) = 0.378mA$$

ID,simulation=0.178mA

This is similar as part c. When operating the short channel devices, the formula  $I_D = 0.5 \mu_n C_{ox} W/L (V_{GS} - V_{TH})^2$  is not longer suitable. Instead, it is more precious to use the formula  $I_D = V_{sat} \cdot W \cdot C_{ox} (V_{GS} - V_{TH})$ , which is due to the velocity saturation. And like the result changing from High VGS to LOW VGS, The ID will be lower. It is because  $I_{out} (I_D) = g_m \cdot V_{GS} (V_{in})$  in the small signal model.

```

Hw1_2_VGS=0.8V VDS=1.8V W/L=1.8u/0.18u
.option post
mml vd vg vs gnd n_18_mm w=1.8u l=0.18u AS="0.48u*1.8u" AD="0.48u*1.8u"
PS="0.96u+1.8u" PD="0.96u+1.8u"
*source
vd vd 0 1.8
vg vg 0 0.8
vds vs 0 0
.tran 10n 50u
.lib "/RAID2/COURSE/AICIntro/AICIntro071/U18_model/U18_Spice_model/
mml80_reg18_v124.lib" tt
.end

```



**Lab2 format:**

	<b>W=18um, L=1.8um</b>	<b>W=1.8um, L=0.18um</b>
<b>VGS=1.8V, VDS=1.8V</b>	ID,calculated =2.875mA ID,simulation =2.259mA	ID,calculated =1.148mA ID,simulation =1.135mA
<b>VGS=0.8V, VDS=1.8V</b>	ID,calculated =0.313mA ID,simulation =0.261.5mA	ID,calculated =0.378mA ID,simulation =0.178mA

The calculate and the illustrate is at each part above.

**(3) Describe the observed channel-length modulation effect and velocity saturation effect from the I-V curves.**(Blue curve  $W=1.8\mu$   $L=0.18\mu$ , Red curve  $W=18\mu$   $L=0.18\mu$ )

1.Hspice code:

**Red curve long channel:**

```
Hw1_3
.option post

*circuit
mm vd vg vs gnd n_18_mm l=1.8u w=18u AS="0.48u*18u" AD="0.48u*18u" PS="0.96u+18u"
PD="0.96u+18u"

*source
vdd vd gnd dd
vgg vg gnd 1.8
vss vs gnd 0

.dc dd 0 1.8 1m

.lib "/RAID2/COURSE/AICIntro/AICIntro071/U18_model/U18_Spice_model/mm180_reg18_v124.lib"
tt
.end
```

**Blue curve short channel:**

```
Hw1_33
.option post

*circuit
mm vd vg vs gnd n_18_mm l=0.18u w=1.8u AS="0.48u*1.8u" AD="0.48u*1.8u" PS="0.96u+1.8u"
PD="0.96u+1.8u"

*source
vdd vd gnd dd
vgg vg gnd 1.8
vss vs gnd 0

.dc dd 0 1.8 1m

.lib "/RAID2/COURSE/AICIntro/AICIntro071/U18_model/U18_Spice_model/mm180_reg18_v124.lib"
tt
.end
```

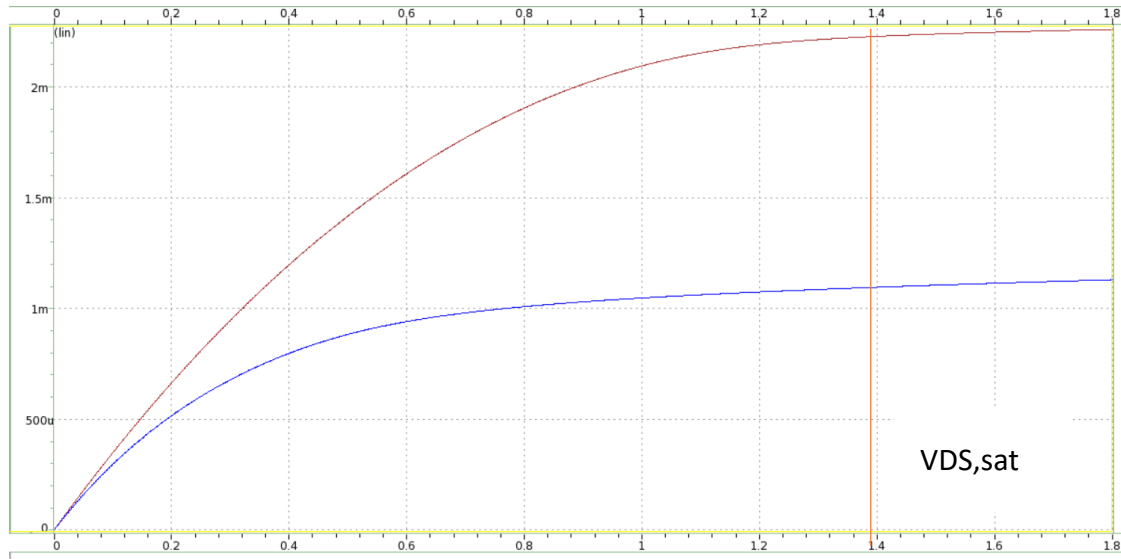


### 2.3. Simulation result and illustrate:

#### (4) channel-length modulation effect (Blue curve $W=1.8\mu$ $L=0.18\mu$ , Red curve $W=18\mu$ $L=0.18\mu$ )

Even when  $V_{DS} \geq V_{DS,sat}$ , which means the transistor enters the saturation region,  $I_{DS}$  still varies as  $V_{DS}$  increase. This is due to the channel length modulation. When  $V_{DS}$  getting bigger and bigger, the  $L_{eff}$  will become shorter and shorter. Thus, the speed of the carriers going through the channel will be faster, that is,  $I_D$  will still increase.

We observe that the effect of channel length modulation is more significant on the short channel device. This is because  $\lambda$  is proportional to  $1/L$ .



#### velocity saturation effect (Blue curve $W=1.8\mu$ $L=0.18\mu$ , Red curve $W=18\mu$ $L=0.18\mu$ )

The velocity saturation effect happens on the short channel device. It goes in the saturation region when  $V_{DS}$  didn't reach  $V_{DS,sat}$ . That is, Short channel devices increasing  $V_{DS}$  may reach the velocity saturation before the transistor pinch off. Therefore,  $I_D$  may approximate a constant at an early time. This result can be used to illustrate Lab1. and Lab 2. above. In Lab2. Part (c) and part(d), it shows us how this effect influence the  $I_D$  so much.

